

Issue Classification

Application/Control No.

10661225

Applicant(s)/Patent Under Reexamination

NGUYEN ET AL.

Examiner

Nguyen, Hiep

Art Unit

2816

ORIGINAL

CLASS

SUBCLASS

327

172

INTERNATIONAL CLASSIFICATION

CLAIMED

NON-CLAIMED

H 0 3 K

7 / 08 (2006.01.01)

CROSS REFERENCE(S)

CLASS

SUBCLASS (ONE SUBCLASS PER BLOCK)

327

171

173

174

175

175

Nguyen, Hiep

09-20-07

(Assistant Examiner)

(Date)

Total Claims Allowed:

42

Annette Smith
(Legal Instruments Examiner)9/24/07
(Date)TUAN T. LAM
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(Primary Examiner)

9/20/07
(Date)

O.G. Print Claim(s)

1

O.G. Print Figure

2C